

## Electron Microscope Facility - rates from July 1st, 2019

Instruments \$/hr or \$/use	Academic (Univ. & Govt.)	Commercial (Inst. only)
JEOL 8900 Probe	56	157.5
FEI XL30 SEM	56	157.5
Zeiss 1550VP SEM	72	202.5
Hitachi 4300 SEM	72	202.5
FEI SCIOS FIB	89	247.5
JEOL 2100 TEM	72	202.5
JEOL ARM (S)TEM	105	292.5
<b>Fischione Nanomill</b>	<b>81</b>	<b>225</b>
<b>Coaters</b>	<b>8</b>	<b>22.5</b>
<b>Electropolishing</b>	<b>8</b>	<b>22.5</b>
<b>Hitachi ion mill</b>	<b>16</b>	<b>45</b>